FORM PTO-1449 (REV. 7-80)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF DOCUMENTS CITED BY APPLICANT

(Use several sheets if necessary)

ATTY. DOCKET NO.	SERIAL NO.
TI-14124D.4	div. of 10/649,274
APPLICANT: Lee D. Whetsel	
FILING DATE: October 20, 2003	GROUP: ~~TBD~~ 2133

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
CB		EP 0,310,152	4/5/1989	Europe	G01	R31/28	X
CB		JP 01-038674 A	2/8/1989	Japan	G01R	31/28	X
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CB		JP 01-068167 A	3/14/1989	Japan	H04M	3/22	X
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